第228回触媒化学研究センター談話会

演題：Characterization of Complex Oxides using Advanced Diffraction and Imaging Techniques

講演者：Douglas J. Buttrey
北海道大学触媒化学研究センター特任教授
Center for Catalytic Science and Technology, Department of Chemical Engineering, University of Delaware, USA

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場所：北海道大学創成科学研究棟4階セミナー室A

要旨：
Two examples of complex oxide structural and compositional analysis will be used to illustrate the capabilities of modern diffraction and imaging techniques. The first case will be that of layered perovskites of the type $Ln_{2-x}Sr_xNiO_{4+}$ (where $Ln$ = La, Pr, Nd, ... and Y), which are of interest both as model systems for understanding strongly correlated 2D electron systems and as potential fuel cell materials. The second example will involve the Mo-V-(Nb,Ta)-Te-O materials that are of interest for alkane selective oxidation and ammoxidation. High resolution TEM and STEM methods, including aberration-corrected HAADF-STEM, will be used in combination with x-ray and neutron diffraction for the analysis of these challenging materials systems.

《連絡先》触媒化学研究センター　触媒物質化学研究部門
上田　渉 （011-706-9164）

主催：触媒化学研究センター